Hybrid 8j366 Traveler

May 22, 2000

1 Connectivity

Repairs on shorts:
Fixes for opens:

2 Chips

The following chips were assembled on this hybrid (in the order that the chips get read out):
Hybrid 8J366 has die: 168-126 168-127 168-128 168-129 206-096 206-097 206-100 206-101

3 Data Analysis Summary

The following summarizes the findings of the Burn-in data analysis program. The first chip in the readout name is numbered 0.

```
% Hybrid 8j366 classification info. Created 12:06:01 05/22/00

Hybrid 8j366 quality: fair
Chip classification: good good good good fair fair good fair
Bad channels (chip-channel): 4-45 5-47 5-106 7-19 7-29
Bad cells: none
Random bad capacitors (chip-cell-channel): 5-1-106 5-10-106 5-11-106
   5-14-106 5-15-106 5-2-106 5-20-106 5-21-106 5-23-106 5-25-106 5-27-106
   5-28-106 5-30-106 5-39-106 5-40-106 5-41-106 5-44-106 5-9-106
Channels at pedestal needed for DCMS: 34.6 35.6 33.6 33.5 30.8 32.5 30.7 31.6
```

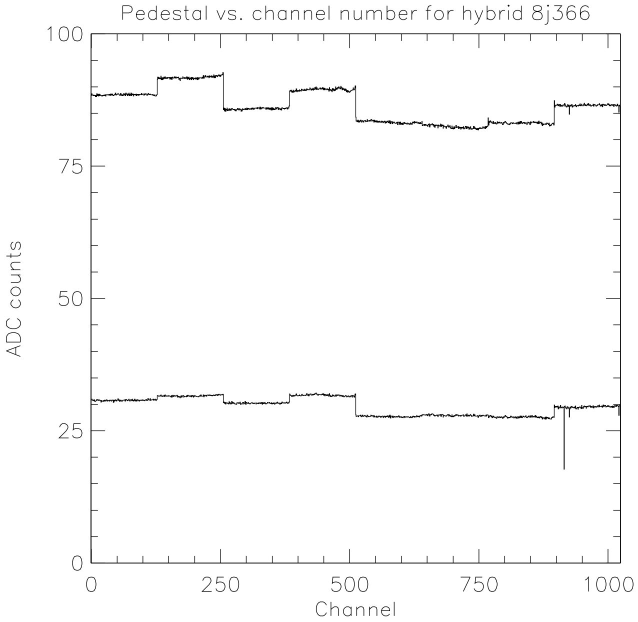
4 Comments

HV tested.

5 Pedestal

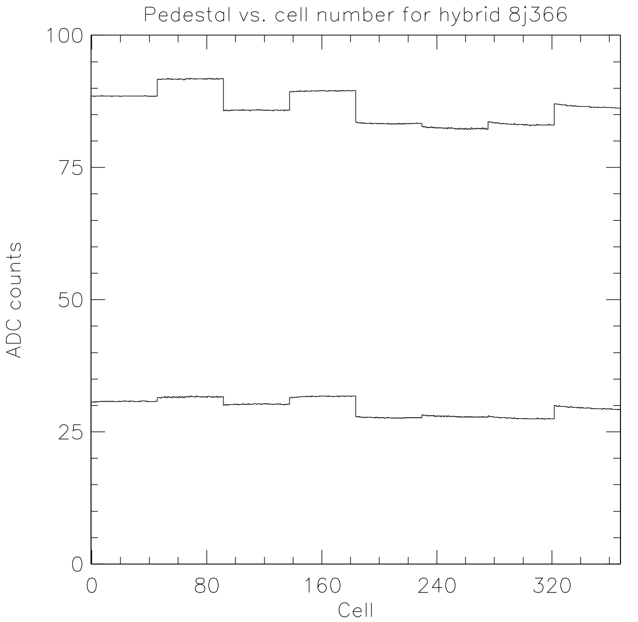
The following plot shows the pedestals vs. channel number with and without charge injection:

Pedestal for each Channel



The following plot shows the average pedestal vs. pipeline cell ID with and without charge injection. The x-axis is cell ID offset by 46 for each chip. Thus cell ID 5 for chip 1 is at x=5, chip 2 at x=51, chip 3 at x=97, etc.

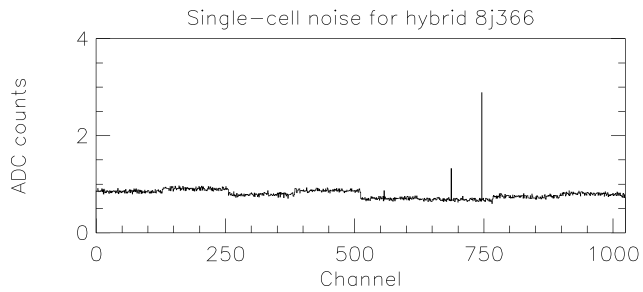
Pedestal vs. Pipeline Cell ID

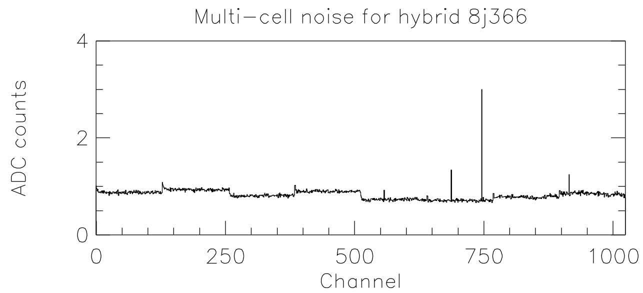


6 Noise

The following plots show the single-cell and multi-cell RMS noise:

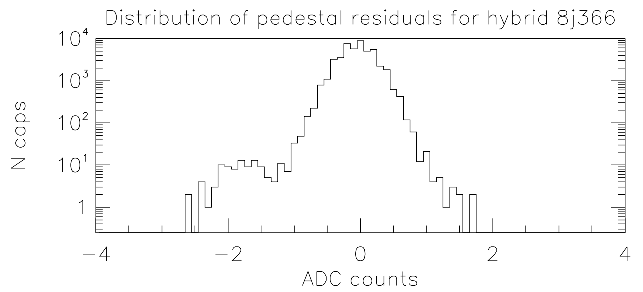
RMS Noise

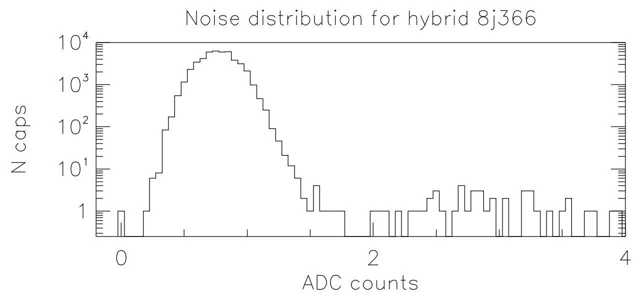




The following are histograms of the pedestal of each pipeline capacitor relative to the chip average (top); and the RMS noise of each capacitor (bottom):

Distribution of Pedestals and Noise





7 Currents

The following plots show the supply currents per chip as a function of measurment number. Currents are measured approximately every 10 minutes:

Supply Currents During Burn-in